

IN THE CLAIMS:

Claim 1 (original): Method enabling a command to switch the measure mode to be entered in a dimension-measuring column provided with a probe tip,
wherein said command to switch the measure mode is entered by only making use of the position of said probe tip.

Claim 2 (original): The method of claim 1, wherein said command to switch the measure mode is entered by pressing the probe tip against a piece to be measured during a time interval greater than a predetermined value.

Claim 3 (original): The method of claim 2, wherein a measurement of the probing point is effected when the probe tip is pressed against said piece to be measured during a time interval shorter than said predetermined value.

Claim 4 (canceled).

Claim 5 (canceled).

Claim 6 (canceled).

Claim 7 (canceled).

Claim 8 (canceled).

Claim 9 (canceled).

Claim 10 (canceled).

Claim 11 (canceled).

Claim 12 (original): The method of claim 1, wherein an aural and/or visual signal is emitted during a said mode switch.

Claim 13 (currently amended): The method of claim 4 12, wherein said command to switch the measure mode is entered by pressing the probe tip against a piece to be measured during a time interval greater than a predetermined value.

Claim 14 (original): The method of claim 1, wherein an aural and/or visual signal is emitted during a said mode switch.

Claim 15 (canceled).

Claim 16 (canceled).

Claim 17 (original): Dimension-measuring column, comprising:
a probe tip designed for being brought into contact with the piece to be measured,
a displacement mechanism of said probe tip,
a measuring and displaying system that allows the position of said probe tip to be determined and displayed, said measuring and displaying system being able to function according to several distinct modes,
wherein at least one of said measure modes can be selected by acting on the position of the probe tip, without any other handling operating being necessary.

Claim 18 (original): The measuring column of claim 17, wherein said measure mode can be selected by pressing the probe tip against the piece to be

measured during a time interval greater than a predetermined value.

Claim 19 (original): The measuring column of claim 18, wherein the measurement of the probing point is effected when the probe tip is pressed against said piece to be measured during a time interval shorter than said predetermined value.

Claim 20 (canceled).

Claim 21 (canceled).

Claim 22 (canceled).

Claim 23 (canceled).

Claim 24 (canceled).

Claim 25 (canceled).

Claim 26 (canceled).

Claim 27 (canceled).

Claim 28 (original): The measuring column of claim 17, comprising a loudspeaker to emit a sound signal during said mode switch.

Claim 29 (original): Computer data carrier comprising a command program for measuring and displaying system in a dimension-measuring column, said

program enabling the position of the probe tip of said measuring column to be determined and displayed, said program being capable of making said measuring and displaying system function according to several distinct modes,

wherein said program enables another of said measure modes to be selected by acting on the position of the probe tip.

Claim 30 (new): Method enabling a command to switch a measure mode to be entered in a dimensional-measuring column provided with a probe tip,

wherein said command to switch the measure mode is entered by means of deliberate handling operations of a height-command crank.

Claim 31 (new): Method according to claim 30, wherein said command to switch the measure mode results in modifying the measuring accuracy and/or resolution.

Claim 32 (new): The method according to claim 30, wherein a status of the display of said dimension-measuring column is modified following said command to switch the measure mode so as to indicated the status of a pressing force of said probe tip against a piece to be measured.

Claim 33 (new): The method of claim 30, wherein said command to switch the measure mode is entered by pressing said probe tip against a piece to be measured during a time interval shorter than a predetermined value.

Claim 34 (new): Dimension-measuring column, comprising:
a probe tip designed for being brought into contact with a piece to be measured,
a height-command crank for displacing said probe tip,

a measuring and displaying system that allows the position of said probe tip to be determined and displayed,

wherein a command to switch the measure mode is entered by means of deliberate handling operations of the height-command crank.

Claim 35 (new): The dimension-measuring column of claim 34, wherein said mode switch command results in modifying the measuring accuracy and/or resolution.

Claim 36 (new): Method enabling a command to switch the measure mode to be entered in a dimension-measuring column provided with a probe tip,

wherein said dimension-measuring column enables detecting a pressing force between the probe tip and a piece to be measured;

wherein said command to switch the measure mode is entered by maintaining the probe tip pressed against said piece to be measured during a time interval longer than a predetermined time greater than zero.

Claim 37 (new): Dimension-measuring column, comprising:

a probe tip designed for being brought into contact with the piece to be measured,

a height-command crank for displacing said probe tip,

a measuring and displaying system that allows the position of said probe tip to be determined and displayed,

wherein a command to switch the measure mode is entered upon detection of a pressing force between the probe tip and a piece to be measured during a time interval longer than a predetermined time greater than zero.